

Title (en)  
INTERPOSER AND MULTILAYER PRINTED WIRING BOARD

Title (de)  
ZWISCHENGLIED UND MEHRSCHICHTIGE LEITERPLATTE

Title (fr)  
ELEMENT INTERMEDIAIRE ET CARTE A CIRCUIT IMPRIME MULTICOUCHE

Publication  
**EP 1667225 A4 20090401 (EN)**

Application  
**EP 04788014 A 20040922**

Priority

- JP 2004013831 W 20040922
- JP 2003331360 A 20030924
- JP 2003381048 A 20031111

Abstract (en)

[origin: EP1667225A1] Provides an interposer capable of preventing breaking of wiring pattern with an IC chip loaded on a package substrate. Stress due to a difference in thermal expansion coefficient between a multilayer printed wiring board 10 having a large thermal expansion and the IC 110 chip having a small thermal expansion can be absorbed by locating the interposer 70 between the package substrate 10 and the IC chip 110. Particularly by using an insulation substrate 80 whose Young's modulus is 55 to 440Gpa as the insulation substrate constituting the interposer 70, stress is absorbed within the interposer 70.

IPC 8 full level  
**H01L 23/498** (2006.01); **H01L 23/32** (2006.01); **H05K 1/02** (2006.01); **H05K 3/34** (2006.01)

CPC (source: EP US)

**H01L 23/49827** (2013.01 - EP US); **H01L 23/49833** (2013.01 - EP US); **H05K 1/0271** (2013.01 - EP US); **H01L 2224/0554** (2013.01 - EP US); **H01L 2224/05568** (2013.01 - EP US); **H01L 2224/05573** (2013.01 - EP US); **H01L 2224/06131** (2013.01 - EP); **H01L 2224/16** (2013.01 - EP US); **H01L 2924/00014** (2013.01 - EP US); **H01L 2924/01004** (2013.01 - EP US); **H01L 2924/01019** (2013.01 - EP US); **H01L 2924/01078** (2013.01 - EP US); **H01L 2924/01079** (2013.01 - EP US); **H01L 2924/09701** (2013.01 - EP US); **H01L 2924/15311** (2013.01 - EP US); **H05K 1/0306** (2013.01 - EP US); **H05K 3/3436** (2013.01 - EP US); **H05K 3/4602** (2013.01 - EP US); **H05K 2201/10378** (2013.01 - EP US); **H05K 2201/10674** (2013.01 - EP US)

C-Set (source: EP US)

1. **H01L 2924/00014** + **H01L 2224/05599**
2. **H01L 2924/00014** + **H01L 2224/0555**
3. **H01L 2924/00014** + **H01L 2224/0556**

Citation (search report)

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**EP 1667225 A1 20060607**; **EP 1667225 A4 20090401**; JP 4771808 B2 20110914; JP WO2005029581 A1 20071115; KR 20060111449 A 20061027; TW 200522833 A 20050701; TW I299970 B 20080811; US 2006202322 A1 20060914; WO 2005029581 A1 20050331

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**EP 04788014 A 20040922**; JP 2004013831 W 20040922; JP 2005514107 A 20040922; KR 20067005802 A 20060323; TW 93128692 A 20040922; US 56420004 A 20040922